

Resource Summary Report

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Anton Paar: SAXSpoint 5.0

RRID:SCR_025989

Type: Tool

Proper Citation

Anton Paar: SAXSpoint 5.0 (RRID:SCR_025989)

Resource Information

URL: <https://www.anton-paar.com/?eID=documentsDownload&document=66294&L=0>

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Description: Laboratory based X-ray beamline instrument. It performs Small-Angle X-ray Scattering (SAXS) and Wide-Angle X-ray Scattering (WAXS) to analyze the nanostructure of materials without requiring synchrotron facilities. SAXS system resolves nanostructures up to 620 nm. Offers flexible analysis of almost any material under ambient and non-ambient conditions. Number of additional optional features equip SAXSpoint 5.0 for future applications up to the micrometer range (USAXS).

Synonyms: , Anton Paar SAXSpoint 5.0, SAXSpoint 5.0, Small-Angle X-ray Scattering point 5.0

Resource Type: instrument resource

Keywords: scattering measurement, small-angle X-ray scattering, wide-angle X-ray scattering, analyze structure of materials at nanoscale,

Availability: THIS RESOURCE IS NO LONGER IN SERVICE

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/main/PDF/SCR_025989.pdf

Resource Name: Anton Paar: SAXSpoint 5.0

Resource ID: SCR_025989

Alternate IDs: Model_Number_SAXSpoint_5.0

Old URLs: <https://www.anton-paar.com/us-en/products/details/saxspoint-50/>

Record Creation Time: 20241026T053255+0000

Record Last Update: 20260829T183434+0000

Ratings and Alerts

No rating or validation information has been found for Anton Paar: SAXSpoint 5.0.

No alerts have been found for Anton Paar: SAXSpoint 5.0.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.